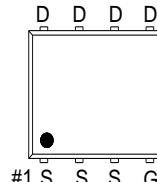
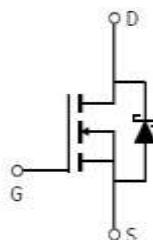


NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PE534SA
PDFN 3x3P
Halogen-Free & Lead-Free****PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	7.5mΩ	52A



G : GATE
D : DRAIN
S : SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ³	I_D	52	A
		33	
		14	
		11	
Pulsed Drain Current ¹	I_{DM}	100	
Avalanche Current	I_{AS}	22	
Avalanche Energy	E_{AS}	24	mJ
Power Dissipation	P_D	36	W
		14	
		2.5	
		1.6	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		50	°C/W
Junction-to-case	$R_{\theta JC}$		3.5	

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design

³Package limitation current is 26A

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.3	1.75	2.35	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}$			0.1	
		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			10	mA
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 10\text{A}$		8.4	10.5	
		$V_{\text{GS}} = 10\text{V}, I_D = 10\text{A}$		6.2	7.5	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 10\text{A}$		40		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1\text{MHz}$		1075		pF
Output Capacitance	C_{oss}			215		
Reverse Transfer Capacitance	C_{rss}			155		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.8		Ω
Total Gate Charge ²	$Q_g(V_{\text{GS}}=10\text{V})$	$V_{\text{DS}} = 15\text{V}, I_D = 10\text{A}$		22.5		nC
	$Q_g(V_{\text{GS}}=4.5\text{V})$			11.7		
Gate-Source Charge ²	Q_{gs}			3.3		
Gate-Drain Charge ²	Q_{gd}			5.3		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$			18		
Rise Time ²	t_r			10		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$	$V_{\text{DD}} = 15\text{V}$ $I_D \geq 10\text{A}, V_{\text{GEN}} = 10\text{V}, R_G = 6\Omega$		33		nS
Fall Time ²	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current ³	I_S	$I_F = 1\text{A}, V_{\text{GS}} = 0\text{V}$ $I_F = 10\text{A}, dI_F/dt = 100\text{A} / \mu\text{s}$			30	A
Forward Voltage ¹	V_{SD}				0.6	V
Reverse Recovery Time	t_{rr}			11.5		nS
Reverse Recovery Charge	Q_{rr}			2.2		nC

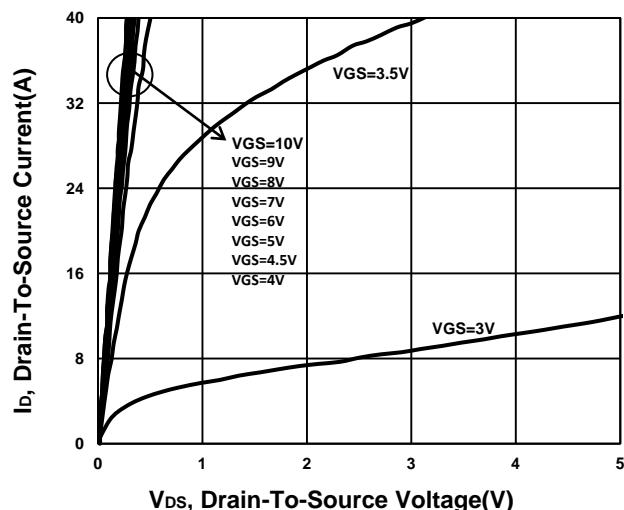
¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current is 26A

NIKO-SEM

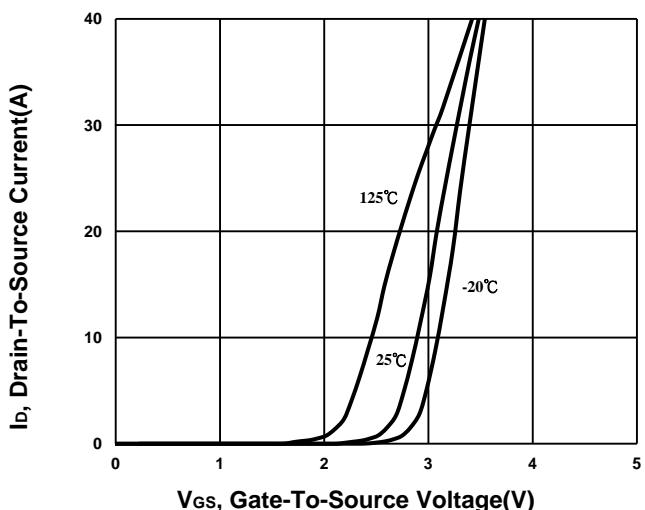
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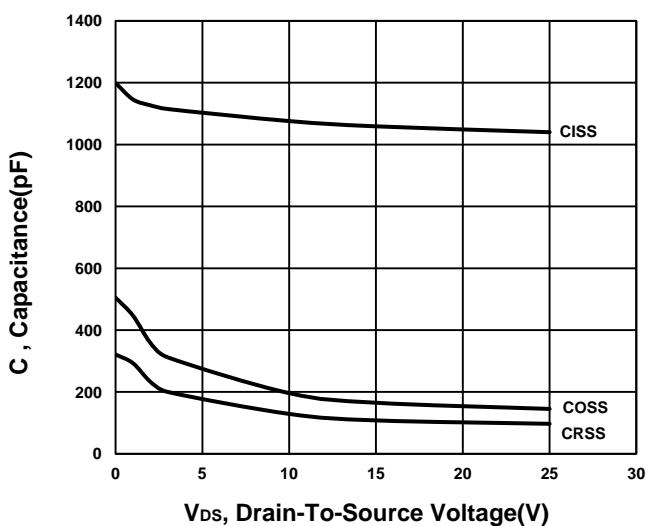
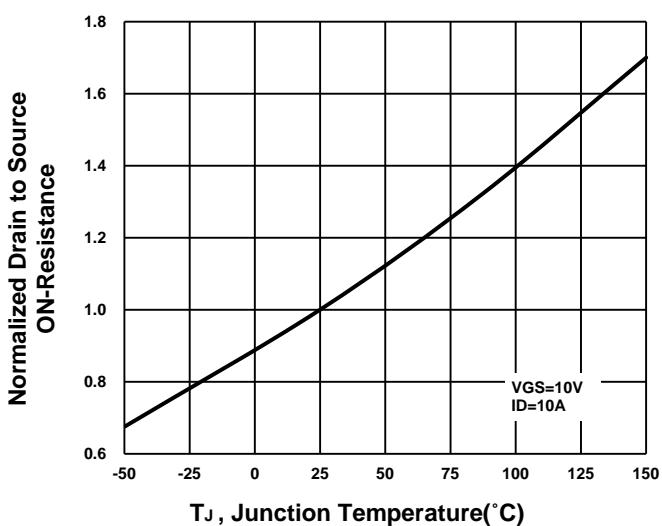
Output Characteristics



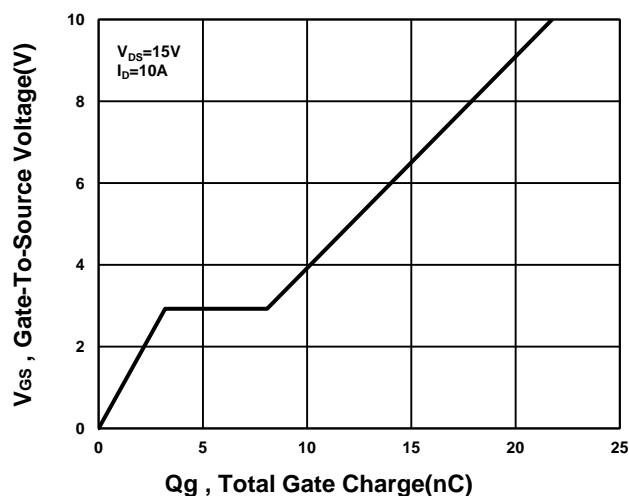
Transfer Characteristics



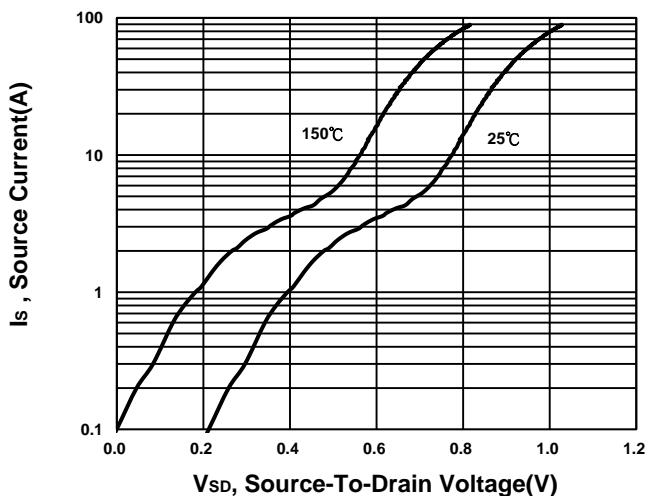
On-Resistance VS Temperature



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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